## **CLAIMS**

1. An apparatus comprising:

an array of memory cells;

- a refresh circuit configured to refresh said array in response to a refresh control signal;
- a first monitor cell configured to have a charge leakage similar to said memory cells;
  - a second monitor cell configured to have a discharge leakage similar to said memory cells;
  - a control circuit configured to generate said refresh control signal in response to either a voltage level of said first monitor cell rising above a first pre-determined threshold level or a voltage level of said second monitor cell dropping below a second pre-determined threshold level, wherein said first and said second threshold levels are different.
  - 2. The apparatus according to claim 1, wherein said control circuit comprises:
  - a first comparator circuit configured to generate a first control signal in response to said voltage level of said first

- 5 monitor cell rising above said first pre-determined threshold level:
  - a second comparator circuit configured to generate a second control signal in response to said voltage level of said second monitor cell rising above said second pre-determined threshold level; and
  - a logic circuit configured to generate said refresh control signal in response to said first and said second control signals.
  - 3. The apparatus according to claim 2, wherein said logic circuit comprises a one-shot circuit configured to generate said refresh control signal having a predetermined pulse width.
  - 4. The apparatus according to claim 1, wherein said control circuit is configured to operate with both symmetrical and asymmetrical charge and discharge leakages.
  - 5. The apparatus according to claim 1, wherein said first monitor cell and said second monitor cell comprise memory cells that are structurally similar to memory cells of said array.

- 6. The apparatus according to claim 5, wherein said monitor cells are configured to have a similar environment to said memory cells of said array.
- 7. The apparatus according to claim 6, wherein a bitline of said first monitor cell and a bitline of said second monitor cell are set to an equalization potential of said array during a monitoring operation.
- 8. The apparatus according to claim 1, further comprising:
- a plurality of monitor cells configured to have a charge leakage similar to said memory cells;
- a plurality of monitor cells configured to have a discharge leakage similar to said memory cells, wherein said control circuit is further configured to generate said refresh control signal in response to any of said monitor cells exceeding a respective one of said first pre-determined threshold level or said second pre-determined threshold level.

- 9. The apparatus according to claim 1, wherein said first monitor cell and said second monitor cell comprise memory cells of said array.
- 10. The apparatus according to claim 1, wherein said array of memory cells comprises 1T memory cells.
- 11. The apparatus according to claim 1, further comprising a sense amplifier configured to program said first monitor cell with a first binary value and said second monitor cell with a second binary value in response to said refresh control signal.
- 12. An apparatus for controlling a refresh of a memory array comprising:

means for monitoring a charge leakage of an array of memory cells;

means for monitoring a discharge leakage of an array of memory cells; and

means for generating a refresh control signal in response to either a voltage level of said first monitoring means rising

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above a first pre-determined threshold level or a voltage level of said second monitoring means dropping below a second pre-determined threshold level, wherein said first and second threshold levels are different.

13. A method for controlling a refresh operation of a memory array comprising the steps of:

monitoring a charge leakage of a first monitor cell;
monitoring a discharge leakage of a second monitor cell;
and

generating a refresh control signal in response to either a voltage level of said first monitor cell rising above a first pre-determined threshold level or a voltage level of said second monitor cell dropping below a second pre-determined threshold level, wherein said first and second pre-determined threshold levels are different.

14. The method according to claim 13, further comprising the steps of:

programming said first monitor cell with a first binary value; and

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programming said second monitor cell with a complement of said first binary value.

15. The method according to claim 13, further comprising the step of:

equalizing a bitline voltage level of said first monitor cell and a bitline voltage level of said second monitor cell with a bitline equalization voltage level of said memory array.

16. The method according to claim 13, further comprising the steps of:

generating a first control signal in response to a comparison of a voltage level of said first monitor cell to said first pre-determined threshold level; and

generating a second control signal in response to a comparison of a voltage level of said second monitor cell to said second pre-determined threshold level.

17. The method according to claim 13, further comprising the step of:

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generating said refresh control signal having a predetermined pulse width.

18. The method according to claim 13, further comprising the step of:

selecting said first and said second predetermined threshold levels to provide a margin between a refresh operation and a loss of retention.

- 19. The method according to claim 18, wherein said first and said second predetermined thresholds are selected to balance maximizing a period between refresh operations and providing said margin.
- 20. The method according to claim 13, Further comprising the step of:

refreshing a first stored value of said first monitor cell and a second stored value of said second monitor cell in response to said refresh control signal.